

**SN5410, SN54LS10, SN54S10,
SN7410, SN74LS10, SN74S10**
TRIPLE 3-INPUT POSITIVE-NAND GATES
DECEMBER 1983—REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

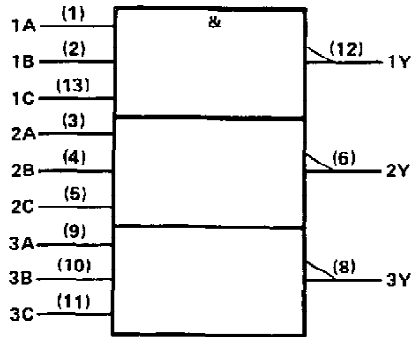
These devices contain three independent 3-input NAND gates.

The SN5410, SN54LS10, and SN54S10 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7410, SN74LS10, and SN74S10 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)

INPUTS			OUTPUT
A	B	C	Y
H	H	H	L
L	X	X	H
X	L	X	H
X	X	L	H

logic symbol†

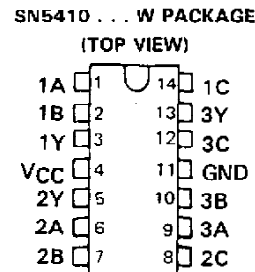
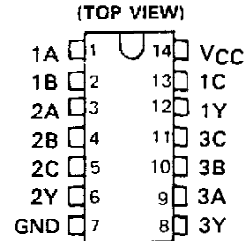


†This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, and N packages.

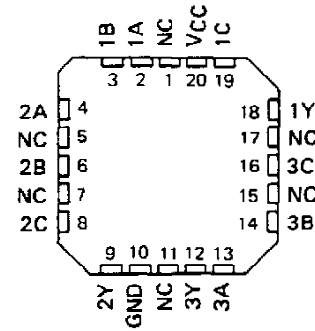
positive logic

$$Y = \overline{A \cdot B \cdot C} \text{ or } Y = \overline{A} + \overline{B} + \overline{C}$$

- SN5410 . . . J PACKAGE
- SN54LS10, SN54S10 . . . J OR W PACKAGE
- SN7410 . . . N PACKAGE
- SN74LS10, SN74S10 . . . D OR N PACKAGE

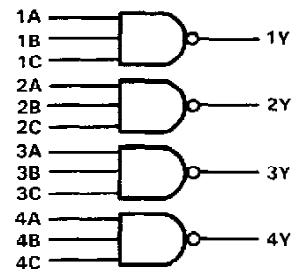


- SN54LS10, SN54S10 . . . FK PACKAGE
(TOP VIEW)



NC - No internal connection

logic diagram (positive logic)

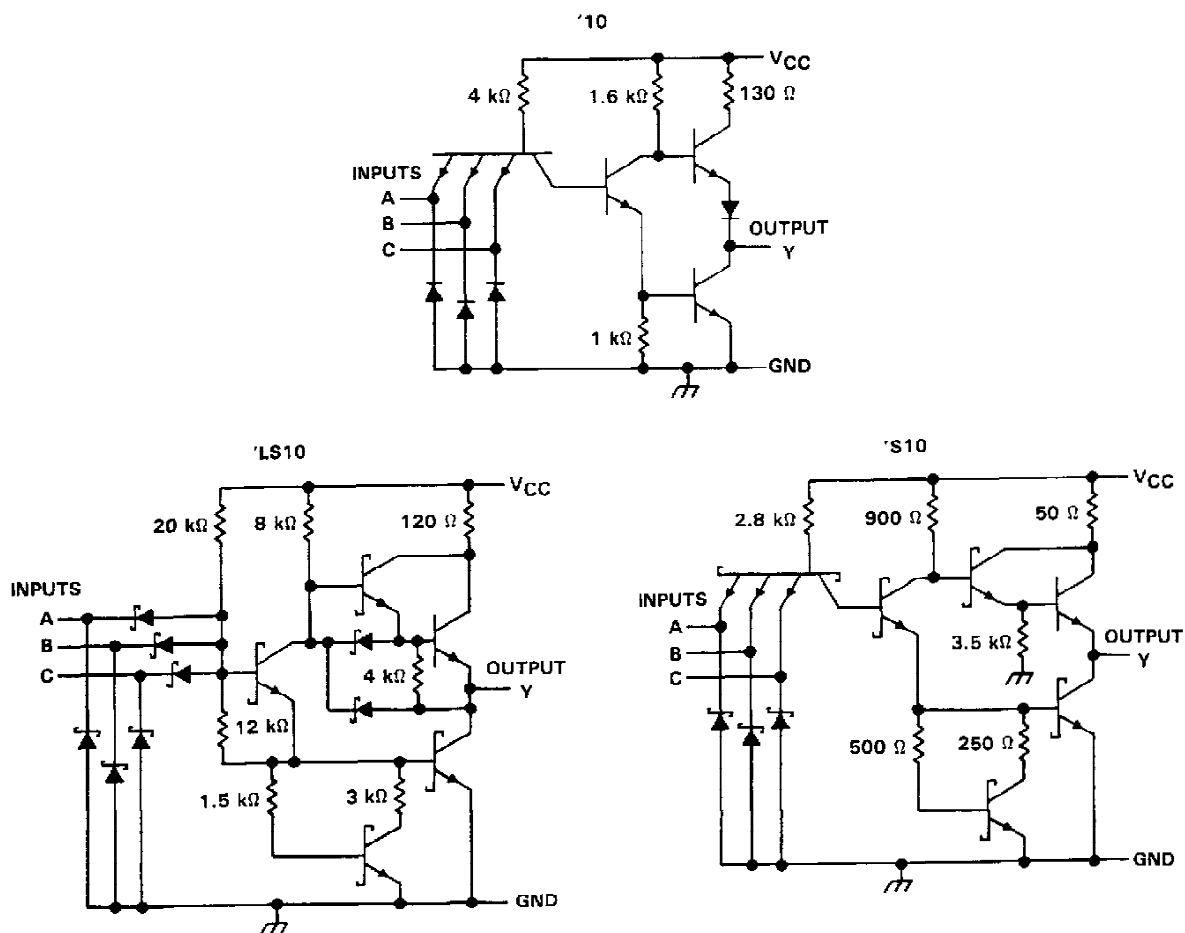


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**SN5410, SN54LS10, SN54S10,
SN7410, SN74LS10, SN74S10
TRIPLE 3-INPUT POSITIVE-NAND GATES**

schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	7 V
Input voltage: '10, 'S10	5.5 V
'LS10	7 V
Operating free-air temperature range: SN54'	-55 °C to 125 °C
SN74'	0 °C to 70 °C
Storage temperature range	-65 °C to 150 °C

NOTE 1: Voltage values are with respect to network ground terminal.



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SN5410, SN7410
TRIPLE 3-INPUT POSITIVE-NAND GATES

recommended operating conditions

	SN5410			SN7410			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage	0.8			0.8			V
I_{OH} High-level output current	-0.4			-0.4			mA
I_{OL} Low-level output current	16			16			mA
T_A Operating free-air temperature	-55 125			0 70			°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN5410			SN7410			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V_{IK}	$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$	-1.5			-1.5			V
V_{OH}	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OH} = -0.4 \text{ mA}$	2.4	3.4		2.4	3.4		V
V_{OL}	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 16 \text{ mA}$	0.2 0.4			0.2 0.4			V
I_I	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$	1			1			mA
I_{IH}	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$	40			40			µA
I_{IL}	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$	-1.6			-1.6			mA
$I_{OS} §$	$V_{CC} = \text{MAX}$	-20		-55	-18		-55	mA
I_{CCH}	$V_{CC} = \text{MAX}, V_I = 0 \text{ V}$	3 6			3 6			mA
I_{CCL}	$V_{CC} = \text{MAX}, V_I = 4.5 \text{ V}$	9 16.5			9 16.5			mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$.

§ Not more than one output should be shorted at a time.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	A, B or C	Y	$R_L = 400 \Omega,$	$C_L = 15 \text{ pF}$		11	22	ns
t_{PHL}					7	15	ns	

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



SN54LS10, SN74LS10

TRIPLE 3-INPUT POSITIVE-NAND GATES

recommended operating conditions

	SN54LS10			SN74LS10			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.7			0.8	V
I _{OH} High-level output current			-0.4			-0.4	mA
I _{OL} Low-level output current			4			8	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54LS10		SN74LS10		UNIT		
		MIN	TYP‡	MAX	MIN		TYP‡	MAX
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.5		-1.5	V	
V _{OH}	V _{CC} = MIN, V _{IL} = MAX, I _{OH} = -0.4 mA	2.5	3.4		2.7	3.4	V	
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 4 mA		0.25	0.4		0.4	V	
	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 8 mA				0.25	0.5		
I _I	V _{CC} = MAX, V _I = 7 V			0.1		0.1	mA	
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			20		20	µA	
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-0.4		-0.4	mA	
I _{OS} §	V _{CC} = MAX	-20		-100	-20	-100	mA	
I _{CCH}	V _{CC} = MAX, V _I = 0 V		0.6	1.2		0.6	1.2	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		1.8	3.3		1.8	3.3	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t _{PLH}	A, B or C	Y	R _L = 2 kΩ,	C _L = 15 pF		9	15	ns
t _{PHL}						10	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

TEXAS
INSTRUMENTS

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SN54S10, SN74S10
TRIPLE 3-INPUT POSITIVE-NAND GATES

recommended operating conditions

	SN54S10			SN74S10			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
I _{OH} High-level output current			-1			-1	mA
I _{OL} Low-level output current			20			20	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54S10			SN74S10			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.2			-1.2	V
V _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, I _{OH} = -1 mA	2.5	3.4		2.7	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 20 mA			0.5			0.5	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			50			50	µA
I _{IL}	V _{CC} = MAX, V _I = 0.5 V			-2			-2	mA
I _{OS} §	V _{CC} = MAX	-40		-100	-40		-100	mA
I _{CCH}	V _{CC} = MAX, V _I = 0 V		7.5	12		7.5	12	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		15	27		15	27	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	A, B or C	Y	R _L = 280 Ω, C _L = 15 pF		3	4.5	ns
t _{PHL}					3	5	ns
t _{PLH}			R _L = 280 Ω, C _L = 50 pF		4.5		ns
t _{PHL}					5		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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